

SPECIFICATIONS

PXI-6552

100 MHz, 20-Channel PXI Digital Waveform Instrument

These specifications apply to the PXI-6552 with 1 MBit, 8 MBit, and 64 MBit of memory per channel.



Hot Surface If the PXI-6552 has been in use, it may exceed safe handling temperatures and cause burns. Allow the PXI-6552 to cool before removing it from the chassis.



Note All values were obtained using a 1 m cable (SHC68-C68-D4 recommended). Performance specifications are not guaranteed when using longer cables.

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Definitions

Warranted specifications describe the performance of a model under stated operating conditions and are covered by the model warranty.

The following characteristic specifications describe values that are relevant to the use of the model under stated operating conditions but are not covered by the model warranty.

- *Typical* specifications describe the performance met by a majority of models.
- *Nominal* specifications describe an attribute that is based on design, conformance testing, or supplemental testing.

Conditions

Typical values are representative of an average unit operating at room temperature.

Channels

Data

Number of channels	20
Direction control	Per channel Per cycle Bidirectional

Programmable Function Interface (PFI)

Number of channels	4
Direction control	Per channel

Clock terminals

Input	3
Output	2

Generation Channels

Channels	Data DDC CLK OUT PFI <0..3>
Signal type	Single-ended
Total programmable voltage levels ¹	1 voltage low level 1 voltage high level
Generation voltage features (into 1 M Ω)	
Range	-2.0 V to 5.5 V
Range restrictions	
<50 MHz clock rate	-0.5 V to 5.5 V -2.0 V to 3.7 V
50 MHz to 100 MHz clock rate	-0.5 V to 3.7 V
Swing	
<50 MHz clock rate	400 mV to 6 V
50 MHz to 100 MHz clock rate	400 mV to 4.2 V
Level resolution	10 mV
DC generation accuracy	± 20 mV (does not include system crosstalk)
Output impedance	
Magnitude	50 Ω (at 25 $^{\circ}$ C), nominal
Temperature coefficient	0.2 $\Omega/^{\circ}$ C, typical
Maximum DC drive strength	
Per channel	± 50 mA
All data, clock, and PFI channels	± 600 mA
Data channel driver enable/disable control	Per channel Per cycle
Channel power-on state ²	Drivers disabled, 50 k Ω input impedance
Output protection	
Range	-2.0 V to 5.5 V
Duration	Indefinite

¹ For all data, CLK OUT (Sample clock only), and PFI channels: while you can only set one voltage low level and one voltage high level for all generation channels, you can set a different low voltage low level and voltage high level for all acquisition channels. You can also set the channels to the high-impedance state (tristate).

² For module assemblies C and later. Module assemblies A and B have an input impedance of 10 k Ω .

Acquisition Channels

Channels	Data STROBE PFI <0..3>
Voltage comparators per channel	2
Total programmable thresholds ³	1 voltage low threshold 1 voltage high threshold
Voltage range	-2.0 V to 5.5 V
Voltage characteristics (10 k Ω input impedance)	
Minimum detectable swing ⁴	50 mV
Threshold resolution	10 mV
DC threshold accuracy ⁵	± 30 mV
Input impedance ⁶	50 Ω nominal or 50 k Ω (default)
Input protection range ⁷	-2.3 V to 6.8 V

Hardware Comparison

Error FIFO depth	4,094
Number of repeated errors	255
Speed	100 MHz, maximum

³ While you can set only one voltage low level and one voltage high level for all acquisition channels, you can set a different voltage low level and voltage high level for all generation channels. You can also set the channels to a high-impedance state (tristate).

⁴ Measured with 50% duty cycle input signal.

⁵ Does not include system crosstalk.

⁶ Software-selectable per channel when powered on and within valid range. For module assembly revisions C and later. Module assemblies A and B have an input impedance of 50 Ω nominal or 10 k Ω (default).

⁷ Diode clamps in the design may provide additional protection outside the specified range.

Timing

Sample Clock

Sources

1. On Board clock (internal voltage-controlled crystal oscillator [VCXO] with divider)
2. CLK IN (SMB jack connector)
3. PXI_STAR (PXI backplane)
4. STROBE (DDC connector; acquisition only)

Frequency range

On Board clock	48 Hz to 50 MHz, Configurable to 200 MHz/ N ; where $2 \leq N \leq 4,194,304$
CLK IN	20 kHz to 50 MHz
PXI_STAR	48 Hz to 50 MHz
STROBE	48 Hz to 50 MHz

Relative delay adjustment

Range	0.0 to 1.0 Sample clock periods
Resolution	10 ps

Exported Sample clock

Destinations ⁹	1. DDC CLK OUT (DDC connector), 2. CLK OUT (SMB jack connector)
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Delay (δ_C), for clock frequencies ≥ 25 MHz

Range	0.0 to 1.0 Sample clock periods
Resolution	1/256 of Sample clock period

Jitter, using On Board clock

Period	20 ps _{rms} , typical
Cycle-to-cycle	35 ps _{rms} , typical

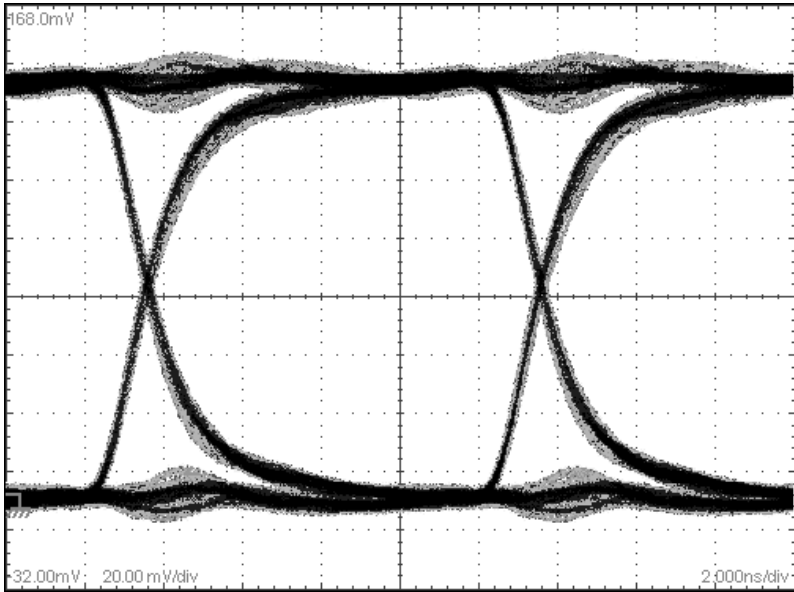
⁸ You can apply a delay or phase adjustment to the On Board clock to align multiple devices.

⁹ Sample clocks with sources other than STROBE can be exported.

Generation Timing

Channels	Data
	DDC CLK OUT PFI <0..3>
Data channel-to-channel skew	±300 ps, typical ±900 ps, maximum
Maximum data channel toggle rate	25 MHz
Data format	Non-return to zero (NRZ)
Data position modes	Sample clock rising edge Sample clock falling edge Delay from Sample clock rising edge
Generation data delay (δ_G), for clock frequencies ≥ 25 MHz	
Range	0.0 to 1.0 Sample clock periods
Resolution	1/256 of Sample clock period

Figure 1. Eye Diagram



Note This eye diagram was captured on DIO 0 (100 MHz clock rate) at 3.3 V at room temperature into 50 Ω termination.

Rise and fall times, 0 V to 3.3 V swing¹⁰

Into 50 Ω

Rise time 2.25 ns

Fall time 2.25 ns

Into 1 M Ω and 475 pF test system capacitance

Rise time 2.75 ns

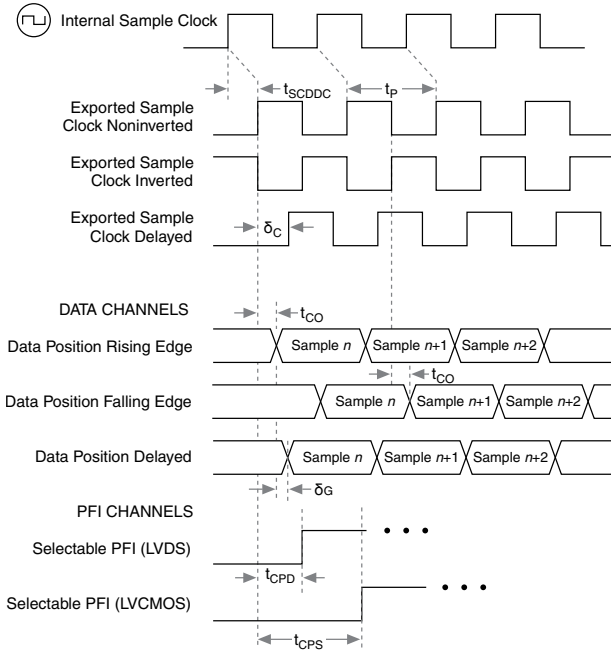
Fall time 2.75 ns

Exported Sample clock offset (t_{CO}) Software-selectable: 0 ns or 2.5 ns (default)

Time delay from Sample clock (internal) to DDC connector (t_{SCDDC}) 32.5 ns, typical

¹⁰ 20% to 80%, typical.

Figure 2. Generation Timing Diagram



t_{SCDDC} = Time Delay from Sample Clock (Internal) to DDC Connector Exported Sample Clock

$0 \leq \delta_C \leq 1$: Exported Sample Clock Delay (Fraction of t_p)

$0 \leq \delta_G \leq 1$: Pattern Generation Data Delay (Fraction of t_p)

$t_p = \frac{1}{f_s}$ = Period of Sample Clock

t_{CO} = Exported Sample Clock Offset

t_{CPD} = Exported Sample Clock to Selectable PFI Offset (LVDS)

t_{CPS} = Exported Sample Clock to Selectable PFI Offset (LVCMOS)

Acquisition Timing

Channels

Data

STROBE

PFI <0..3>

Channel-to-channel skew

± 400 ps, typical

± 900 ps, maximum

Data position modes, per channel

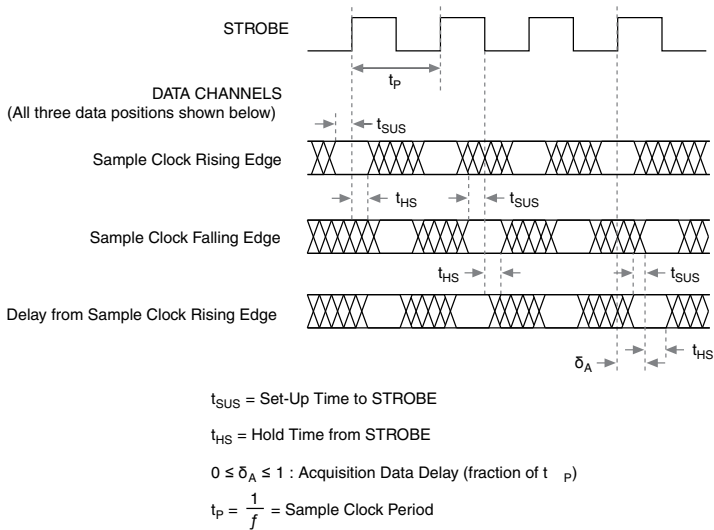
Sample clock rising edge

Sample clock falling edge

Delay from Sample clock rising edge

Minimum detectable pulse width ¹¹	4 ns
Setup and hold times	
To STROBE ¹²	
Setup time (t_{SUS})	2.3 ns, maximum
Hold time (t_{HS})	1.9 ns, maximum
To Sample clock ¹³	
Setup time (t_{SUSC})	0.4 ns
Hold time ($t_{HS C}$)	0 ns
Time delay from DDC connector data to internal Sample clock (t_{DDCSC})	27.5 ns, typical
Acquisition data delay (δ_A), for clock frequencies ≥ 25 MHz	
Range	0.0 to 1.0 Sample clock periods
Resolution	1/256 of Sample clock period

Figure 3. Acquisition Timing Diagram Using STROBE as the Sample Clock



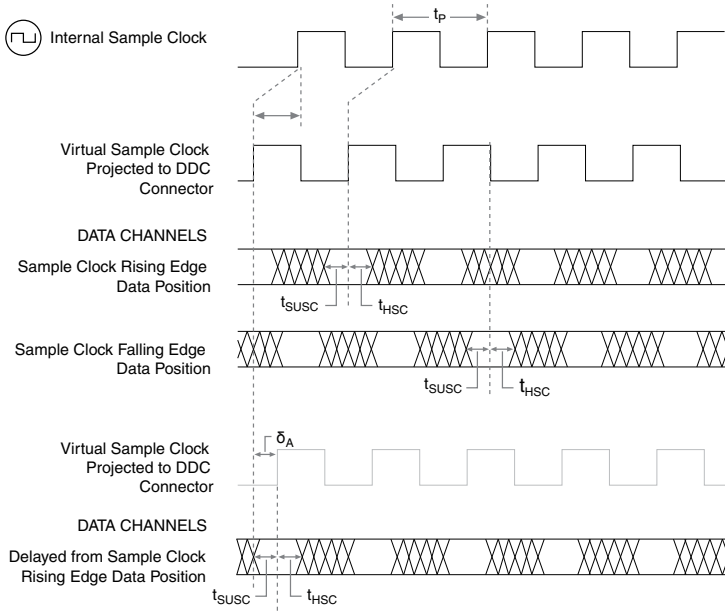
Note Provided setup and hold times account for maximum channel-to-channel skew and jitter.

¹¹ Required at both acquisition voltage thresholds.

¹² Includes maximum data channel-to-channel skew.

¹³ Does not include data channel-to-channel skew, t_{DDCSC} , or t_{SCDDC} .

Figure 4. Acquisition Timing Diagram with Sample Clock Sources Other than STROBE



t_{DDCSC} : Time Delay from DDC Connector to Internal Sample Clock

$0 \leq \delta_A \leq 1$: Acquisition Data Delay (fraction of t_p)

$t_p = \frac{1}{f}$ = Period of Sample Clock

t_{SUSC} = Set-Up Time to Sample Clock

t_{HSC} = Hold Time to Sample Clock

CLK IN

Connector	SMB jack
Direction	Input
Destinations	1. Reference clock for the phase-locked loop (PLL) 2. Sample clock
Input coupling	AC
Input protection	± 10 VDC
Input impedance	Software-selectable: 50 Ω (default) or 1 k Ω

Minimum detectable pulse width ¹⁴	4 ns
Clock requirements	Free-running (continuous) clock

As Sample Clock

Table 1. External Sample Clock Range

Voltage Range (V_{pk-pk})	Sine Wave	Square Wave	
	Frequency Range	Frequency Range	Duty Cycle
0.65 to 5.0	5.5 MHz to 50 MHz	20 kHz to 50 MHz	$f < 50$ MHz: 25% to 75% $f \geq 50$ MHz: 40% to 60%
1.0 to 5.0	3.5 MHz to 50 MHz	—	—
2.0 to 5.0	1.8 MHz to 50 MHz	—	—

As Reference Clock

Frequency range	10 MHz \pm 50 ppm
Voltage range	0.65 V_{pk-pk} to 5.0 V_{pk-pk}
Duty cycle	25% to 75%

STROBE

Connector	DDC
Direction	Input
Destinations	Sample clock (acquisition only)
Frequency range	48 Hz to 50 MHz
Duty cycle range ¹⁵	
$f \leq 50$ MHz	25% to 75%
$f > 50$ MHz	40% to 60%
Minimum detectable pulse width ¹⁶	4 ns
Voltage thresholds	Refer to <i>Acquisition Timing</i> in the <i>Timing</i> section.

¹⁴ Required at V_{rms} mean.

¹⁵ At the programmed thresholds.

¹⁶ Required at both acquisition voltage thresholds.

Clock requirements	Free-running (continuous) clock
Input impedance ¹⁷	Software-selectable: 50 Ω or 50 kΩ (default)

PXI_STAR

Connector	PXI backplane
Direction	Input
Destinations	<ol style="list-style-type: none"> 1. Sample clock 2. Start trigger 3. Reference trigger (acquisition sessions only) 4. Advance trigger (acquisition sessions only) 5. Pause trigger (generation sessions only) 6. Script trigger <0..3> (generation sessions only)
Frequency range	48 Hz to 50 MHz
Clock requirements	Free-running (continuous) clock

CLK OUT

Connector	SMB jack
Direction	Output
Sources	<ol style="list-style-type: none"> 1. Sample clock (excluding STROBE) 2. Reference clock (PLL)
Output impedance	50 Ω, nominal
As Sample clock	
Electrical characteristics	Refer to Generation Channels in the <i>Channels</i> section.
As Reference clock	
Maximum drive current	24 mA
Logic type	3.3 V CMOS

DDC CLK OUT

Connector	DDC
Direction	Output

¹⁷ For module assemblies C and later. Module assemblies A and B have an input impedance of 50 Ω or 10 kΩ (default).

Source ¹⁸	Sample clock
Electrical characteristics	Refer to <i>Generation Timing</i> in the <i>Timing</i> section.

Reference Clock (PLL)

Sources ¹⁹	<ol style="list-style-type: none"> PXI_CLK10 (PXI backplane) CLK IN (SMB jack connector) None (On Board clock not locked to a reference)
Destination	CLK OUT (SMB jack connector)
Lock time	400 ms, typical
Frequencies	10 MHz \pm 50 ppm
Duty cycle range	25% to 75%

Waveform

Memory and Scripting

Memory architecture	The PXI-6552 uses Synchronization and Memory Core (SMC) technology in which waveforms and instructions share onboard memory. Parameters such as number of script instructions, maximum number of script instructions, maximum number of waveforms in memory, and number of samples (S) available for waveform storage are flexible and user defined.
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Onboard memory size ²⁰	
1 Mbit/channel	
Acquisition	1 Mbit/channel (4 MBytes total)
Generation	1 Mbit/channel (4 MBytes total)
8 Mbit/channel	
Acquisition	8 Mbit/channel (32 MBytes total)
Generation	8 Mbit/channel (32 MBytes total)

¹⁸ STROBE cannot be routed to DDC CLK OUT.

¹⁹ The source provides the reference frequency for the PLL.

²⁰ Maximum limit for generation sessions assumes no scripting instructions.

64 Mbit/channel	
Acquisition	64 Mbit/channel (256 MBytes total)
Generation	64 Mbit/channel (256 MBytes total)
Generation	
Single waveform mode	Generates a single waveform once, n times, or continuously.
Scripted mode ²¹	Generates a simple or complex sequence of waveforms.
Finite repeat count	1 to 16,777,216
Waveform quantum	Waveform must be an integer multiple of 2 S (samples). ²²

Table 2. Generation Minimum Waveform Size, Samples (S)²³

Configuration	Sample Rate	
	100 MHz	50 MHz
Single waveform	2 S	2 S
Continuous waveform	32 S	16 S
Stepped sequence	128 S	64 S
Burst sequence	512 S	256 S

Acquisition	
Minimum record size ²⁴	1 S
Record quantum	1 record
Total records	2,147,483,647, maximum
Total pre-Reference trigger samples	0 up to full record
Total post-Reference trigger samples	0 up to full record

²¹ Use scripts to describe the waveforms to be generated, the order in which the waveforms are generated, how many times the waveforms are generated, and how the device responds to Script triggers.

²² Regardless of waveform size, NI-HSDIO allocates waveforms into block sizes of 32 S of physical memory.

²³ Sample rate dependent. Increasing sample rate increases minimum waveform size.

²⁴ Regardless of waveform size, NI-HSDIO allocates at least 128 bytes for a record.

Triggers

Trigger Types	Sessions	Edge Detection	Level Detection
1. Start	Acquisition and generation	Rising or falling	—
2. Pause	Acquisition and generation	—	High or low
3. Script <0..3>	Generation	Rising or falling	High or low
4. Reference	Acquisition	Rising or falling	—
5. Advance	Acquisition	Rising or falling	—

Sources

1. PFI 0 (SMB jack connector)
2. PFI <1..3> (DDC connector)
3. PXI_TRIG <0..7> (PXI backplane)
4. PXI_STAR (PXI backplane)
5. Pattern match (acquisition sessions only)
6. Software (user function call)
7. Disabled (do not wait for a trigger)

Destinations²⁵

- PFI 0 (SMB jack connector)
 PFI <1..3> (DDC connector)
 PXI_TRIG <0..6> (PXI backplane)

Minimum required trigger pulse width

Generation	30 ns
Acquisition	Acquisition triggers must meet setup and hold time requirements.

²⁵ Each trigger can be routed to any destination except the Pause trigger. The Pause trigger cannot be exported for acquisition sessions.

Table 3. Trigger Rearm Time

Type	Typical	Maximum
Start to Reference	57 S	64 S
Start to Advance	138 S	143 S
Reference to Reference	132 S	153 S

Delay from Pause trigger to Pause state²⁶

Generation sessions	32 Sample clock periods + 150 ns
Acquisition sessions	Data synchronous
Delay from trigger to digital data output	32 Sample clock periods + 160 ns

Events

Types	Sessions
1. Marker <0..3>	Generation
2. Data Active	Generation
3. Ready for Start	Acquisition and generation
4. Ready for Advance	Acquisition
5. End of Record	Acquisition
6. Sample Error	Hardware comparison
7. Delayed Data Active	Hardware comparison

Destinations²⁷

1. PFI 0 (SMB jack connector)
2. PFI <1..3> (DDC connector)
3. PXI_TRIG <0..7> (PXI backplane)

Marker time resolution (placement)

Markers must be placed at an integer multiple of 2 S (samples).

²⁶ Use the Data Active event during generation to determine when the PXI-6552 enters the Pause state.

²⁷ Except for the Data Active event, each event can be routed to any destination. The Data Active event can be routed only to the PFI channels.

Calibration

Interval for external calibration	2 years
Warm-up time	15 minutes
Onboard calibration voltage reference	
Temperature coefficient	±5 ppm/°C
Long-term stability	90 ppm/ \sqrt{kHr} , typical
On Board clock characteristics (valid only when PLL reference source is set to None)	
Frequency accuracy	±100 ppm, typical
Temperature stability	±30 ppm, typical
Aging	±5 ppm first year, typical

Software

Driver Software

Driver support for this device was first available in NI-HSDIO 1.0.

NI-HSDIO is an IVI-compliant driver that allows you to configure, control, and calibrate the PXI-6552. NI-HSDIO provides application programming interfaces for many development environments.

Application Software

NI-HSDIO provides programming interfaces, documentation, and examples for the following application development environments:

- LabVIEW
- LabWindows™/CVI™
- Measurement Studio
- Microsoft Visual C/C++
- .NET (C# and VB.NET)

NI Measurement Automation Explorer

NI Measurement Automation Explorer (MAX) provides interactive configuration and test tools for the PXI-6552. MAX is included on the NI-HSDIO media.

Power

VDC	Current, Typical	Current, Maximum
+3.3 V	2.0 A	2.0 A
+5 V	1.8 A	2.3 A
+12 V	0.3 A	0.5 A
-12 V	0.2 A	0.2 A

Total power 21.6 W, typical
26.5 W, typical

Physical Specifications

Dimensions Single 3U, CompactPCI slot; PXI compatible,
18.6 cm × 13.1 cm

Weight 375 g (13.2 oz)

I/O Connectors

Label	Connector Type	Description
CLK IN	SMB jack	External Sample clock, external PLL reference input
PFI 0		Events, triggers
CLK OUT		Exported Sample clock, exported Reference clock
DIGITAL DATA & CONTROL	68-pin VHDCI connector	Digital data channels, exported Sample clock, STROBE, events, triggers

Environment



Note To ensure that the PXI-6552 cools effectively, follow the guidelines in the *Maintain Forced Air Cooling Note to Users* included with the PXI-6552 or available at ni.com/manuals. The PXI-6552 is intended for indoor use only.

Operating temperature	0 °C to 55 °C in all NI PXI chassis except the following: 0 °C to 45 °C when installed in an NI PXI-1000B or NI PXI-101x chassis
Operating relative humidity	10 to 90% relative humidity, noncondensing (meets IEC 60068-2-56)
Storage temperature	-20 °C to 70 °C
Storage relative humidity	5 to 95% relative humidity, noncondensing (meets IEC 60068-2-56)
Operating shock	30 g, half-sine, 11 ms pulse (meets IEC 60068-2-27; test profile developed in accordance with MIL-PRF-28800F)
Operating vibration	5 Hz to 500 Hz, 0.31 g _{rms} (meets IEC 60068-2-64)
Storage shock	50 g, half-sine, 11 ms pulse (meets IEC 60068-2-27; test profile developed in accordance with MIL-PRF-28800F)
Storage vibration	5 Hz to 500 Hz, 2.46 g _{rms} (meets IEC 60068-2-64; test profile exceeds requirements of MIL-PRF-28800F, Class B)
Altitude	0 to 2,000 m above sea level (at 25 °C ambient temperature)
Pollution degree	2

Compliance and Certifications

Safety

This product is designed to meet the requirements of the following electrical equipment safety standards for measurement, control, and laboratory use:

- IEC 61010-1, EN 61010-1
- UL 61010-1, CSA C22.2 No. 61010-1



Note For UL and other safety certifications, refer to the product label or the [Online Product Certification](#) section.

Electromagnetic Compatibility

This product meets the requirements of the following EMC standards for electrical equipment for measurement, control, and laboratory use:

- EN 61326-1 (IEC 61326-1): Class A emissions; Basic immunity
- EN 55011 (CISPR 11): Group 1, Class A emissions
- AS/NZS CISPR 11: Group 1, Class A emissions
- FCC 47 CFR Part 15B: Class A emissions
- ICES-001: Class A emissions



Note For EMC declarations, certifications, and additional information, refer to the [Online Product Certification](#) section.

To meet EMC compliance, the following cautions apply:



Caution The SHC68-C68-D4 shielded cables must be used when operating the PXI-6552.



Caution EMC filler panels must be installed in all empty chassis slots.

CE Compliance

This product meets the essential requirements of applicable European Directives, as follows:

- 2014/35/EU; Low-Voltage Directive (safety)
- 2014/30/EU; Electromagnetic Compatibility Directive (EMC)

Online Product Certification

Refer to the product Declaration of Conformity (DoC) for additional regulatory compliance information. To obtain product certifications and the DoC for this product, visit ni.com/certification, search by model number or product line, and click the appropriate link in the Certification column.

Environmental Management

NI is committed to designing and manufacturing products in an environmentally responsible manner. NI recognizes that eliminating certain hazardous substances from our products is beneficial to the environment and to NI customers.

For additional environmental information, refer to the *Minimize Our Environmental Impact* web page at ni.com/environment. This page contains the environmental regulations and directives with which NI complies, as well as other environmental information not included in this document.

Waste Electrical and Electronic Equipment (WEEE)



EU Customers At the end of the product life cycle, all NI products must be disposed of according to local laws and regulations. For more information about how to recycle NI products in your region, visit ni.com/environment/weee.

电子信息产品污染控制管理办法（中国 RoHS）



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376877A-01 November 3, 2017